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FORM PTO-1449 (Rev. 7-80)

## S.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

Atty. Docket No. 14641

Serial No. 10/797,607

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**APPLICANT** 

Mandelis et al.

FILING DATE 3/11/2004

GROUP 28.84

U.S. PATENT DOCUMENTS												
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6	<b>AA</b>	5667300	9/16/1997	Mandelis et al.								
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FORM PTO-1449  U.S. DEPARTMENT OF COMMERC PATENT AND TRADEMARK OFFIC								Atty. Docket No.	146		Serial No. 10/797,607				
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